

	Search Terms
1	CAPACITANCE
2	CAPACITANCES
3	CURRENT
4	CURRENTS
5	ELECTROMIGRATION
6	ELECTROMIGRATIONS
7	FLOW
8	FLOWING
9	FLOWINGS
10	FLows
11	MATRICES
12	MATRIX
13	MATRIXES
14	POWER
15	POWERS
16	TEMP
17	TEMPERATURE
18	TEMPERATURES
19	TEMPS
20	THERMAL
21	THERMALS
22	(((ELECTROMIGRATION AND (CAPACITANCE SAME MATRIX)) AND (MATRIX SAME THERMAL)) AND ((FLOWING OR FLOW) SAME (CURRENT OR POWER))) AND (TEMPERATURE SAME (CURRENT OR POWER)))

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1	307464							
2	49908							
3	2734193							
4	377591							
5	10323							
6	22							
7	3363516							
8	953339							
9	55							
10	985917							
11	83531							
12	643815							
13	9633							
14	3504153							
15	111303							
16	845604							
17	3334002							
18	1084110							
19	79680							
20	1331296							
21	300							
22	0							

	Search Terms
1	HABITZ-PETER
2	HABITZ-PETERS
3	HABITZ-PETER.IN.

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2	0							
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 (thermal<paragraph>matrix)  
 <and>capacitance

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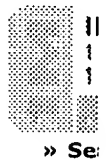
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